TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7WH34FU,TC7WH34FK

Triple Non-Inverter

The TC7WH34 is an advanced high speed CMOS Non-Inverter fabricated with silicon gate CMOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation. The internal circuit is composed of 3 stages including buffer output, which provide high noise immunity and stable output. An input protection circuit ensures that 0 to 7 V can be applied to the input pins without regard to the supply voltage.

This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

Features

- High speed: $t_{pd} = 3.8 \text{ ns}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 2 \mu A (max)$ at $Ta = 25^{\circ}C$
- High noise immunity: $V_{\text{NIH}} = V_{\text{NIL}} = 28\% V_{\text{CC}}$ (min)
- 5.5-V Tolerant inputs.
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2~5.5 V

Marking

TC7WH34FU





Pin Assignment (top view)





Weight SSOP8-P-0.65: 0.02 g (typ.) SSOP8-P-0.50A: 0.01 g (typ.)

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Logic Diagram

1A—	(1)	1	(7) 1Y
2A—	(3)		(5) 2Y
	(6)		(2) 3Y
3A			

А	Y
L	L
Н	Н

Truth Table

Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit	
Supply voltage range	V _{CC}	-0.5~7.0	V	
DC input voltage	V _{IN}	-0.5~7.0	V	
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5	V	
Input diode current	IIК	-20	mA	
Output diode current	I _{OK}	±20	mA	
DC output current	IOUT	±25	mA	
DC V _{CC} /ground current	ICC	±50	mA	
Dewar dissinction	D-	300 (TC7WH34FU)	mW	
Power dissipation	PD	200 (TC7WH34FK)		
Storage temperature	T _{stg}	-65~150	°C	
Lead temperature (10 s)	TL	260	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Operating Ranges

Characteristics	Symbol	Rating	Unit	
Supply voltage	V _{CC}	2.0~5.5	V	
Input voltage	V _{IN}	0~5.5	V	
Output voltage	V _{OUT}	0~V _{CC}	V	
Operating temperature	T _{opr}	-40~85	°C	
Input rise and fall time	dt/dv	0~100 (V_{CC} = 3.3 \pm 0.3 V)	ns/V	
	uuuv	0~20 (V_{CC} = 5 \pm 0.5 V)		

Electrical Characteristics

DC Characteristics

		Test Condition V _{CC} (V)		Ta = 25°C			Ta = -40~85°C			
Characteristics	Symbol			V _{CC} (V)	Min	Тур.	Max	Min	Max	Unit
		_		2.0	1.50	_		1.50	_	v
High-level input voltage	VIH			3.0~ 5.5	V _{CC} × 0.7		_	V _{CC} × 0.7	_	
		_		2.0			0.50		0.50	V
Low-level input voltage	VIL			3.0~ 5.5	_		V _{CC} × 0.3	_	$V_{CC} \times 0.3$	
		V _{IN} = V _{IH}	I _{OH} = -50 μA	2.0	1.9	2.0		1.9		V
				3.0	2.9	3.0		2.9		
High-level output voltage	V _{OH}			4.5	4.4	4.5		4.4	_	
			$I_{OH} = -4 \text{ mA}$	3.0	2.58	_		2.48	_	
			I _{OH} = -8 mA	4.5	3.94	_	_	3.80	—	
	V _{OL}	VIN = VIL	I _{OL} = 50 μA	2.0	_	0.0	0.1	—	0.1	
				3.0	_	0.0	0.1	—	0.1	
Low-level output voltage				4.5	_	0.0	0.1	—	0.1	V
			$I_{OL} = 4 \text{ mA}$	3.0	_		0.36	_	0.44	
			$I_{OL} = 8 \text{ mA}$	4.5	—		0.36		0.44	
Input leakage current	I _{IN}	$V_{IN} = 5.5 V \text{ or GND}$		0~ 5.5	_		±0.1	_	±1.0	μΑ
Quiescent supply current	ent supply current I_{CC} $V_{IN} = V_{CC}$ or GND		5.5			2.0	_	20.0	μA	

AC Characteristics (input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	L L	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit
Characteristics	Symbol		V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Min	Max	Unit
	t _{pLH} t _{pHL}	_	3.3 ± 0.3	15	_	5.0	7.1	1.0	8.5	ns
Propagation delay time				50	_	7.5	10.6	1.0	12.0	
Propagation delay time			5.0 ± 0.5	15	_	3.8	5.5	1.0	6.5	115
				50	_	5.3	7.5	1.0	8.5	
Input capacitance	CIN		_		_	4	10		10	pF
Power dissipation capacitance	C _{PD}			(Note)	_	18	_		_	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/3$

Noise Characteristics (Ta = 25°C, input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Limit	Unit
Quiet output maximum dynamic V_{OL}	V _{OLP}	C _L = 50 pF	5.0	0.3	0.8	V
Quiet output minimum dynamic V_{OL}	V _{OLV}	C _L = 50 pF	5.0	-0.3	-0.8	V
Minimum high level dynamic input voltage	V _{IHD}	C _L = 50 pF	5.0	_	3.5	V
Maximum low level dynamic input voltage	V _{ILD}	C _L = 50 pF	5.0		1.5	V

Input Equivalent Circuit



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Package Dimensions

SSOP8-P-0.65

Unit : mm





Weight: 0.02 g (typ.)

Package Dimensions

SSOP8-P-0.50A

Unit : mm





Weight: 0.01 g (typ.)

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20070701-EN GENERAL

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